T-46-23-05

CY7C167A

CYPRESS SEMICONDUCTOR

16,384 x 1 Static RAM

Features

- **Automatic power-down when deselected**
- **CMOS for optimum speed/power**
- **High speed**
  —15 ns
- **Low active power**
  —275 mW
- **Low standby power**
  —83 mW
- **TTL-compatible inputs and outputs**
- **Capable of withstanding greater than 2001V electrostatic discharge**
- **V_{IH} of 2.2V**

Functional Description

The CY7C167A is a high-performance CMOS static RAM organized as 16,384 words by 1 bit. Easy memory expansion is provided by an active LOW chip enable ($\overline{CE}$) and three-state drivers. The CY7C167A has an automatic power-down feature, reducing the power consumption by 67% when deselected.

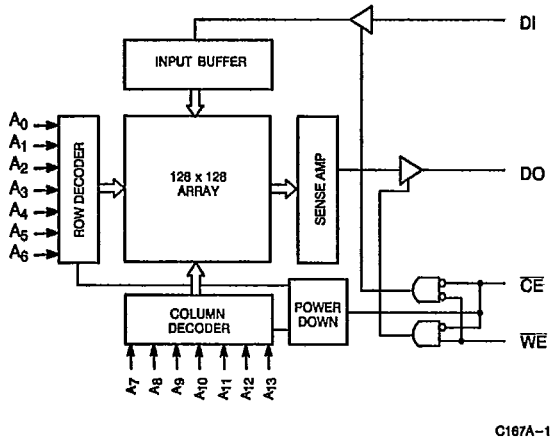
Writing to the device is accomplished when the chip select ($\overline{CE}$) and write enable ($\overline{WE}$) inputs are both LOW. Data on the input pin (DI) is written into the memory location specified on the address pins (A_0 through A_{13}).

Reading the device is accomplished by taking the chip enable ($\overline{CE}$) LOW, while ($\overline{WE}$) remains HIGH. Under these conditions, the contents of the location specified on the address pins will appear on the data output (DO) pin.

The output pin remains in a high-impedance state when chip enable is HIGH, or write enable ($\overline{WE}$) is LOW.

A die coat is used to insure alpha immunity.

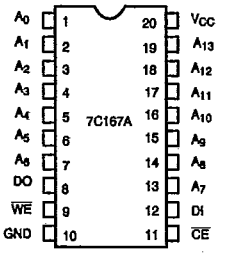
Logic Block Diagram



C167A–1

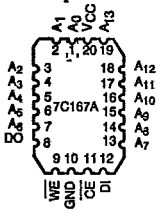
Pin Configurations

DIP
Top View



C167A–2

LCC
Top View



C167A–3

Selection Guide

		7C167A–15	7C167A–20	7C167A–25	7C167A–35	7C167A–45
Maximum Access Time (ns)		15	20	25	35	45
Maximum Operating Current (mA)	Commercial	90	80	60	60	50
	Military		80	70	60	50

Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... −65°C to +150°C

Ambient Temperature with Power Applied ..... −55°C to +125°C

Supply Voltage to Ground Potential (Pin 20 to Pin 10) ..... −0.5V to +7.0V

DC Voltage Applied to Outputs in High Z State ..... −0.5V to +7.0V

DC Input Voltage ..... −3.0V to +7.0V

Output Current into Outputs (LOW) ..... 20 mA

Static Discharge Voltage ..... >2001V (per MIL-STD-883, Method 3015)

Latch-Up Current ..... >200 mA

Operating Range

Range	Ambient Temperature	V_{CC}
Commercial	0°C to +70°C	5V ± 10%
Military[1]	−55°C to +125°C	5V ± 10%

Electrical Characteristics Over the Operating Range[2]

Parameters	Description	Test Conditions		7C167A−15 Min.	7C167A−15 Max.	7C167A−20 Min.	7C167A−20 Max.	7C167A−25 Min.	7C167A−25 Max.	Units
V_{OH}	Output High Voltage	V_{CC} = Min., I_{OH} = −4.0 mA		2..4		2..4		2..4		V
V_{OL}	Output Low Voltage	V_{CC} = Min., I_{OL} = 12.0 mA, 8.0 mA Mil			0.4		0.4		0.4	V
V_{IH}	Input High Voltage			2.2	V_{CC}	2.2	V_{CC}	2.2	V_{CC}	V
V_{IL}	Input Low Voltage[3]			−0.5	0.8	−0.5	0.8	−0.5	0.8	V
I_{IX}	Input Load Current	GND ≤ V_I ≤ V_{CC}		−10	+10	−10	+10	−10	+10	µA
I_{OZ}	Output Leakage Current	GND ≤ V_O ≤ V_{CC} Output Disabled		−10	+10	−10	+10	−10	+10	µA
I_{OS}	Output Short Circuit Current[4]	V_{CC} = Max., V_{OUT} = GND			−350		−350		−350	mA
I_{CC}	V_{CC} Operating Supply Current	V_{CC} = Max., I_{OUT} = 0 mA	Com'l		90		80		60	mA
			Mil				80		70	
I_{SB}	Automatic CE Power-Down Current[5]	Max. V_{CC}, $\overline{CE}$ ≥ V_{IH}	Com'l		40		40		20	mA
			Mil				40		20	

Parameters	Description	Test Conditions		7C167A−35 Min.	7C167A−35 Max.	7C167A−45 Min.	7C167A−45 Max.	Units
V_{OH}	Output High Voltage	V_{CC} = Min., I_{OH} = −4.0 mA		2..4		2..4		V
V_{OL}	Output Low Voltage	V_{CC} = Min., I_{OL} = 12.0 mA, 8.0 mA Mil			0.4		0.4	V
V_{IH}	Input High Voltage			2.2	V_{CC}	2.2	V_{CC}	V
V_{IL}	Input Low Voltage[3]			−0.5	0.8	−0.5	0.8	V
I_{IX}	Input Load Current	GND ≤ V_I ≤ V_{CC}		−10	+10	−10	+10	µA
I_{OZ}	Output Leakage Current	GND ≤ V_O ≤ V_{CC} Output Disabled		−10	+10	−10	+10	µA
I_{OS}	Output Short Circuit Current[4]	V_{CC} = Max., V_{OUT} = GND			−350		−350	mA
I_{CC}	V_{CC} Operating Supply Current	V_{CC} = Max., I_{OUT} = 0 mA	Com'l		60		50	mA
			Mil		60		50	
I_{SB}	Automatic CE Power-Down Current[5]	Max. V_{CC}, $\overline{CE}$ ≥ V_{IH}	Com'l		20		15	mA
			Mil		20		20	

Notes:

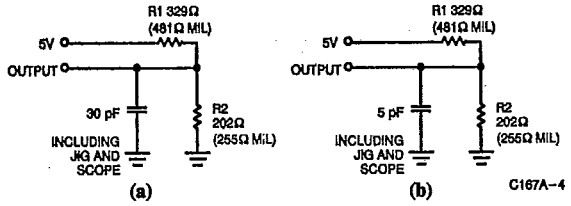
1. T_A is the "instant on" case temperature.
2. See the last page of this specification for Group A subgroup testing information.
3. V_{IL} min. = −3.0V for pulse durations less than 30 ns.
4. Duration of the short circuit should not exceed 30 seconds.
5. A pull-up resistor to V_{CC} on the $\overline{CE}$ input is required to keep the device deselected during V_{CC} power-up, otherwise I_{SB} will exceed values given.

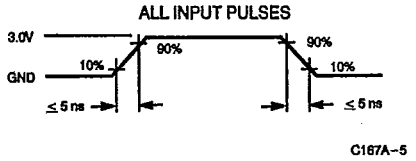
SRAMs

Capacitance[6]

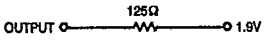
Parameters	Description	Test Conditions	Max.	Units
C_{IN}	Input Capacitance	$T_A = 25°C$, f = 1 MHz, $V_{CC} = 5.0V$	10	pF
C_{OUT}	Output Capacitance		10	pF
C_{CE}	Chip Enable Capacitance		6	pF

AC Test Loads and Waveforms

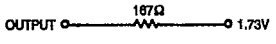




Equivalent to: THÉVENIN EQUIVALENT



Commercial



Military

Switching Characteristics Over the Operating Range[2, 7]

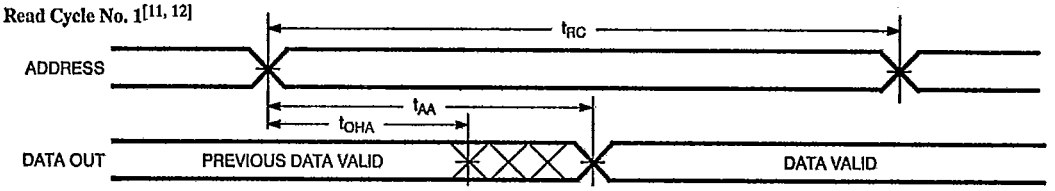
Parameters	Description		7C167A–15		7C167A–20		7C167A–25		7C167A–35		7C167A–45		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
READ CYCLE													
t_{RC}	Read Cycle Time	Com'l	15		20		25		30		40		ns
		Mil			20		25		35		40		ns
t_{AA}	Address to Data Valid	Com'l		15		20		25		30		40	ns
		Mil				20		25		35		40	ns
t_{OHA}	Data Hold from Address Change		5		5		5		5		5		ns
t_{ACE}	$\overline{CE}$ LOW to Data Valid			15		20		25		35		45	ns
t_{LZCE}	$\overline{CE}$ LOW to Low Z[8]		5		5		5		5		5		ns
t_{HZCE}	$\overline{CE}$ HIGH to High Z[8, 9]			8		8		10		15		15	ns
t_{PU}	$\overline{CE}$ LOW to Power-Up		0		0		0		0		0		ns
t_{PD}	$\overline{CE}$ HIGH to Power-Down			15		20		20		20		25	ns
WRITE CYCLE[10]													
t_{WC}	Write Cycle Time		15		20		20		25		40		ns
t_{SCE}	$\overline{CE}$ LOW to Write End		12		15		20		25		30		ns
t_{AW}	Address Set-Up to Write End		12		15		20		25		30		ns
t_{HA}	Address Hold from Write End		0		0		0		0		0		ns
t_{SA}	Address Set-Up to Write Start		0		0		0		0		0		ns
t_{PWE}	$\overline{WE}$ Pulse Width		12		15		15		20		20		ns
t_{SD}	Data Set-Up to Write End		10		10		10		15		15		ns
t_{HD}	Data Hold from Write End		0		0		0		0		0		ns
t_{HZWE}	$\overline{WE}$ LOW to High Z[8, 9]			7		7		7		10		15	ns
t_{LZWE}	$\overline{WE}$ HIGH to Low Z[8]		5		5		5		5		5		ns

Notes:

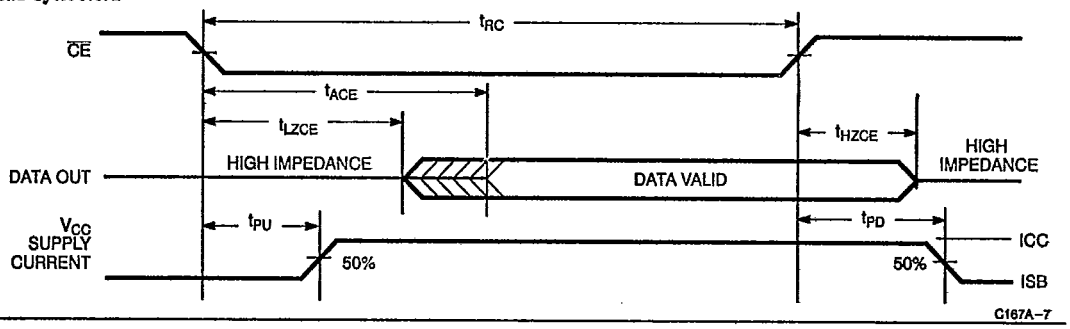
6. Tested initially and after any design or process changes that may affect these parameters.
7. Test conditions assume signal transition times of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.
8. At any given temperature and voltage condition, t_{HZ} is less than t_{LZ} for any given device.
9. t_{HZCE} and t_{HZWE} are tested with $C_L = 5$ pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady state voltage.
10. The internal write time of the memory is defined by the overlap of $\overline{CE}$ LOW and $\overline{WE}$ LOW. Both signal must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.

Switching Waveforms

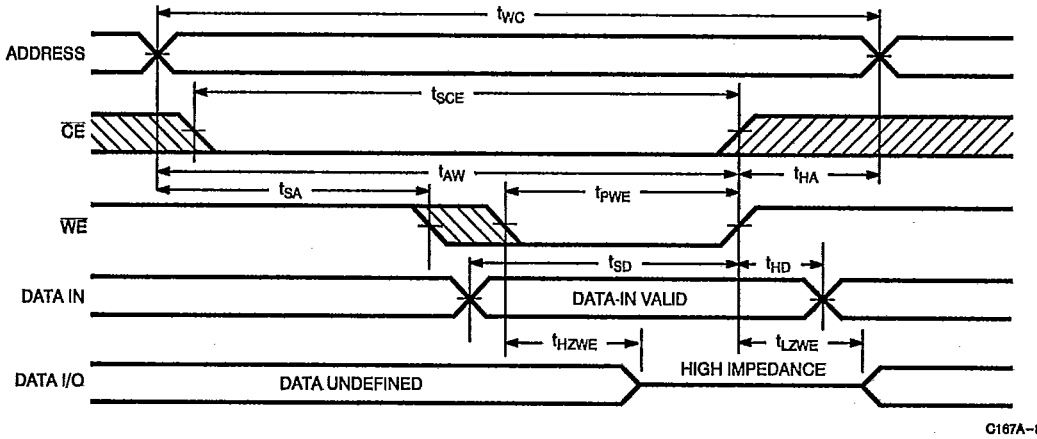
Read Cycle No. 1[11, 12]



Read Cycle No. 2[11, 13]



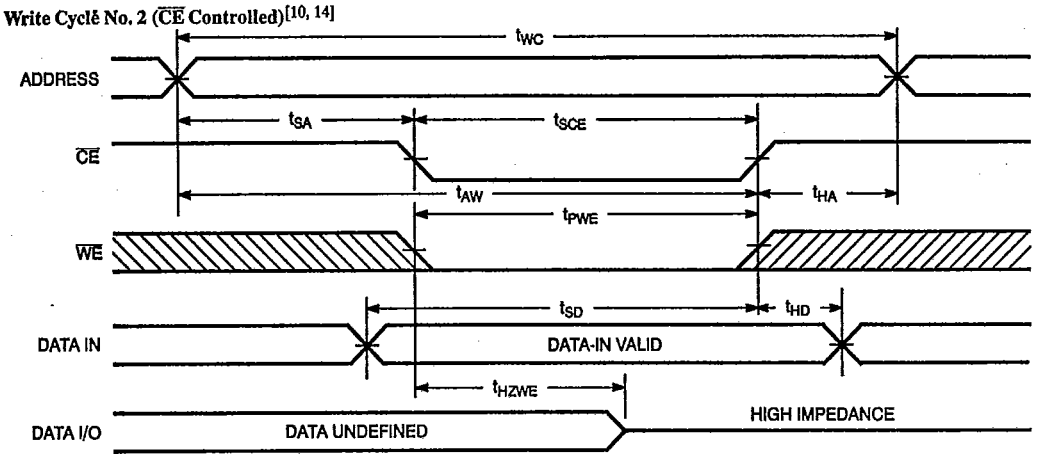
Write Cycle No. 1 ($\overline{WE}$ Controlled)[10]



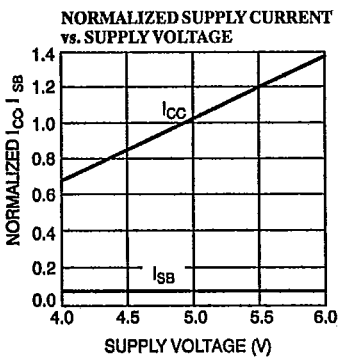
Notes:
11. $\overline{WE}$ is high for read cycle.
12. Device is continuously selected, $\overline{CE} = V_{IL}$.
13. Address valid prior to or coincident with $\overline{CE}$ transition LOW.
14. If $\overline{CE}$ goes HIGH simultaneously with $\overline{WE}$ HIGH, the output remains in a high-impedance state.

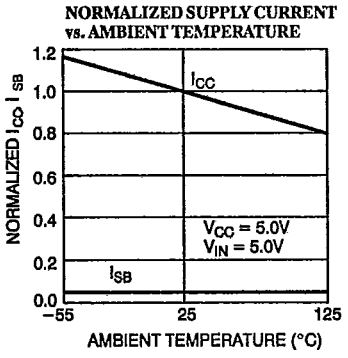
Switching Waveforms (continued)

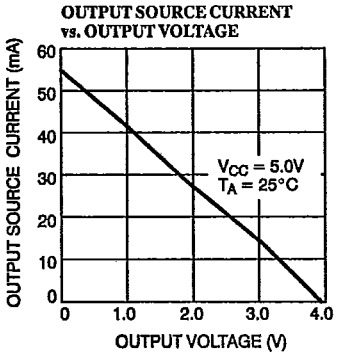
Write Cycle No. 2 ($\overline{CE}$ Controlled)[10, 14]

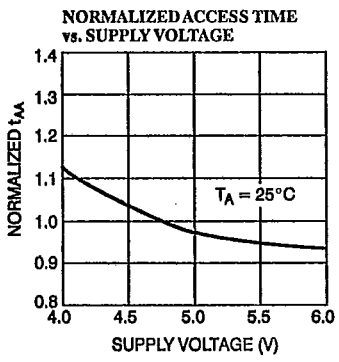


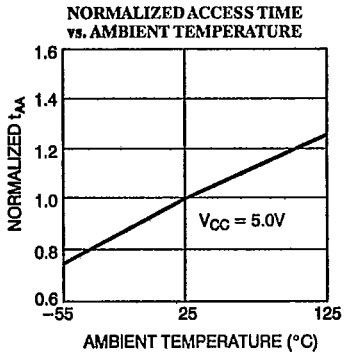
Typical DC and AC Characteristics

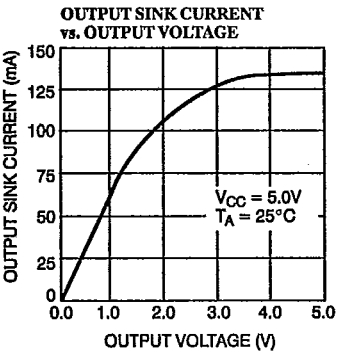






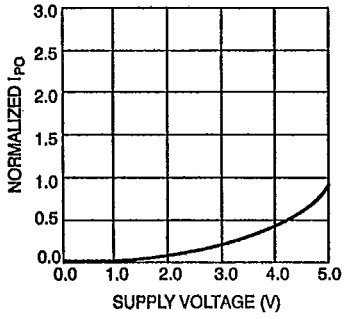




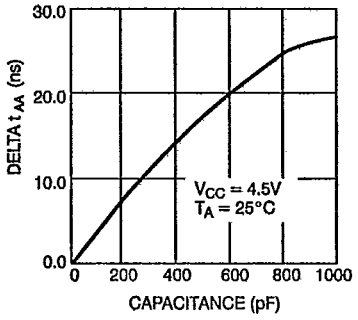


Typical DC and AC Characteristics (continued)

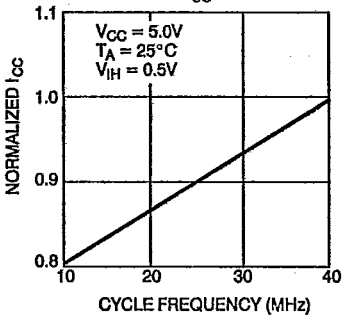
TYPICAL POWER-ON CURRENT vs. SUPPLY VOLTAGE



TYPICAL ACCESS TIME CHANGE vs. OUTPUT LOADING



NORMALIZED I_{CC} vs. CYCLE TIME



SRAMs

Ordering Information

Speed (ns)	I_{CC} (mA)	Ordering Code	Package Type	Operating Range
15	80	CY7C167A-15PC	P5	Commercial
		CY7C167A-15DC	D6	
		CY7C167A-15VC	V5	
20	80	CY7C167A-20PC	P5	Commercial
		CY7C167A-20DC	D6	
		CY7C167A-20LC	L51	
		CY7C167A-20VC	V5	
		CY7C167A-20DMB	D6	Military
		CY7C167A-20LMB	L51	
		CY7C167A-20KMB	K71	
25	60	CY7C167A-25PC	P5	Commercial
		CY7C167A–25DC	D6	
		CY7C167A-25LC	L51	
		CY7C167A-25VC	V5	
		CY7C167A-25DMB	D6	Military
		CY7C167A-25LMB	L51	
		CY7C167A-25KMB	K71	

Speed (ns)	I_{CC} (mA)	Ordering Code	Package Type	Operating Range
35	60	CY7C167A-35PC	P5	Commercial
		CY7C167A-35DC	D6	
		CY7C167A-35LC	L51	
		CY7C167A-35VC	V5	
		CY7C167A-35DMB	D6	Military
		CY7C167A-35LMB	L51	
		CY7C167A-35KMB	K71	
45	50	CY7C167A-45PC	P5	Commercial
		CY7C167A-45DC	D6	
		CY7C167A-45LC	L51	
		CY7C167A-45VC	V5	
		CY7C167A-45DMB	D6	Military
		CY7C167A-45LMB	L51	
		CY7C167A-45KMB	K71	

MILITARY SPECIFICATIONS
Group A Subgroup Testing

DC Characteristics

Parameters	Subgroups
V_{OH}	1,2,3
V_{OL}	1,2,3
V_{IH}	1,2,3
V_{IL} Max.	1,2,3
I_{IX}	1,2,3
I_{OZ}	1,2,3
I_{CC}	1,2,3
I_{SB}	1,2,3

Switching Characteristics

Parameters	Subgroups
READ CYCLE	
t_{RC}	7,8,9,10,11
t_{AA}	7,8,9,10,11
t_{OHA}	7,8,9,10,11
t_{ACE}	7,8,9,10,11
WRITE CYCLE	
t_{WC}	7,8,9,10,11
t_{SCE}	7,8,9,10,11
t_{AW}	7,8,9,10,11
t_{HA}	7,8,9,10,11
t_{SA}	7,8,9,10,11
t_{PWE}	7,8,9,10,11
t_{SD}	7,8,9,10,11
t_{HD}	7,8,9,10,11

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